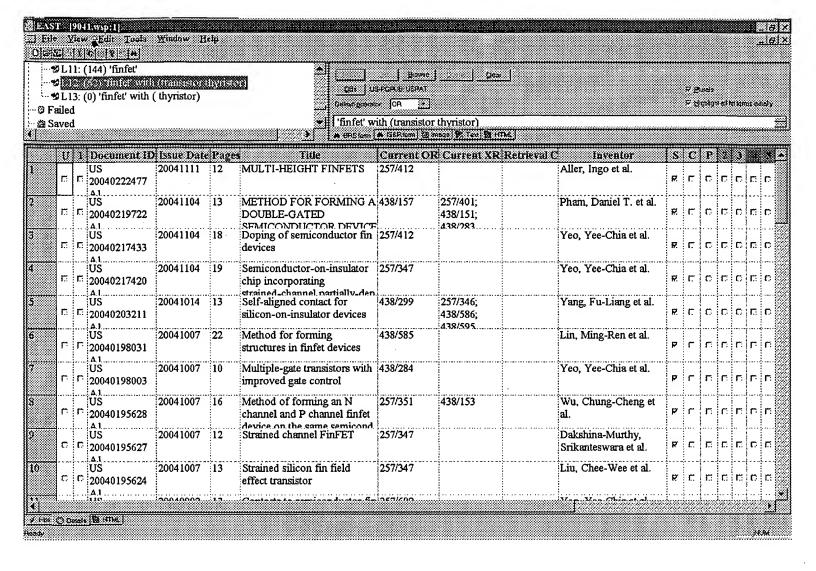
Ref #	Hits	Search Query	DBs	Default Operat or	Plural s	Time Stamp
L1	0	10/629241	US-PGPU B; USPAT, EPO; JPO	OR	ON	2004/11/12 08:29
L2	0	10/629241	US-PGPU B; USPAT	OR	ON	2004/11/12 08:29
L3	0	10/629041	US-PGPU B; USPAT	OR	ON	2004/11/12 09:24
L4	. 5	"6492662"	US-PGPU B; USPAT	OR	ON	2004/11/12 09:27
L5	5	"6458632"	US-PGPU B, USPAT	OR	ON	2004/11/12 09:29
L6	10	"6448586"	US-PGPU B; USPAT	OR	ON	2004/11/12 09:32
L7	44	"6229161"	US-PGPU B, USPAT	OR	ON	2004/11/12 10:22
L8	24	thyristor with transistor.ti.	US-PGPU B; USPAT	OR	ON	2004/11/12 10:23
L9	951	thyristor with transistor clm	US-PGPU B; USPAT	OR	ON	2004/11/12 10:24
L10	64	(thyristor with transistor) with (method process).clm.	US-PGPU B; USPAT	OR	ON	2004/11/12 10:26
L11	144	'finfet'	US-PGPU B; USPAT	OR	ON	2004/11/12 10:48
L12	52	'finfet' with (transistor thyristor)	US-PGPU B; USPAT	OR	ON	2004/11/12 10:52
L13	0	'finfet' with ( thyristor)	US-PGPU B; USPAT	OR	ON	2004/11/12 10:32
L14	40	'finfet'.TI.	US-PGPU B; USPAT	OR	ON	2004/11/12 10:49
L15	0	14 AND ('finfet' WITH THYRISTOR)	US-PGPU B; USPAT	OR	ON	2004/11/12 10:50
L16	0	14 AND (TRANSISTOR WITH THYRISTOR)	US-PGPU B; USPAT	OR	ON	2004/11/12 10:50
L17	O.	14 AND (FINFET WITH (TRANSISTOR WITH THYRISTOR))	US-PGPU B, USPAT	OR	ON	2004/11/12 10:51
L18	0	12 AND THYRISTOR	US-PGPU B; USPAT	OR	ON	2004/11/12 10:52

L19	0 'finfet' with thyristor	US-PGPU	OR	ON	2004/11/12
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11 US 120040169269	20040902 1				Yeo, Yee-Chia et al.	ъ г	1		c r	. C
12 US 20040145019	20040729 1	3 STRAINED CHANNEL FINFET	257/349		Dakshina-Murthy, Srikanteswara et al.	ĸ r	c	r	o ir	n n'
13 US 20040113171	20040617 1	FABRICATING A MOSFET	257/119		Chiu, Hsien-Kuang et al.	K C	C	Г	o r	T C
14 US 20040110331	20040610 1	5 CMOS inverters configured using multiple-gate transistors	438/199	-	Yeo, Yee-Chia et al.	F. C	c	C	c	п C
IS US 20040108559	20040610 4	9 Insulated-gate field-effect transistor, method of	257/411	257/E29.315	Sugii, Nobuyuki et al.	R C	c	С	c r	c c
16 US 20040100306	20040527 1		326/112	257/E27.06; 257/E27.062	Krivokapic, Zoran et al.	ם פ	r	r	r. r	r n
US C 20040048424	20040311 1	6 Method of forming an N channel and P channel FINEET device on the same s	438/154		Wu, Chung Cheng et al.	P	'n	r	г	гп
US C 20040038464	20040226 1		438/151	438/152; 438/168	Fried, David M. et al.	b L	r	r	L: I	rr
19 US 20040036118	20040226 4	18 Concurrent Fin-FET and thick-body device fabrication	257/347	257/E21.415; 257/E21.703; 257/E27.112;	Abadeer, Wagdi W. et al.	<b>8</b> C	i in	Г	n (	СП
20 US 20040033674	20040219 1	4 Deposition of amorphous silicon-containing films	438/478	21/10/2/2/2/2/2	Todd, Michael A.	es u	r	r	r: r	c n
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n		US 20040031979	20040219	64	Strained-semiconductor-on-in sulator device structures	257/233	257/235; 257/297;	Lochtefeld, Anthony J. et al.	₽.	r	ព	r.	c i	Γ.
r		US 20030229661	20031211	16	source follower pass gate	708/710	257/E21.415:	Kim, Jae-Joon et al.	Ŗ	r.	n	L:	c	r:
r		US 20030193058	20031016	15	evaluation tree. Integrated circuit with capacitors having fin structure	257/200		Fried, David M. et al.	₽.	r	c	 [7	c	r:
r		US 20030178670	20030925	14	Finfet CMOS with NVRAM capability	257/315	257/E21.209; 257/E29.302	Fried, David M. et al.	₽.	r.	c	r	c	 r::
г	Γ.	US 20030160233	20030828	13	semiconductor device having	257/37	257/E21.347; 257/E21.415;	Rendon, Michael J. et al.	₽.	r	េ	c	c i	r.:
г		US 20030151077	20030814	16	menerou shearbing layer and Method of forming a vertical double gate semiconductor device and structure thereof	257/250	257/E29.277: 257/270; 257/328;	Mathew, Leo et al.	Þ	r	r	r	n	г
г	r	US 20030145299	20030731	15		716/11	257/331:	Fried, David M. et al.	Þ	٦	г	r	ר	r
٦		US 20030102518	20030605	22	mobility plane for cell	257/401	257/350; 257/368;	Fried, David M. et al.	Þ	۳	r:	r	r:	r
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С		US 20020171107	20021121	6	Method for forming a semiconductor device having	257/347	257/E21.415; 257/E21.43;	Cheng, Baohong et al.	þ	r.	π:	r.	п	c
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